

# CCD linear image sensor



S11151-2048

## High sensitivity in the ultraviolet region, front-illuminated CCD

Despite a front-illuminated CCD, the S11151-2048 offers high sensitivity in the ultraviolet region (200 nm) nearly equal to back-thinned CCD.

### Features

- High sensitivity in the ultraviolet region (spectral response range: 200 to 1000 nm)
- Image lag: 0.1% typ.
- Low dark current
- Low cost

### Applications

- Spectrometers

### Structure

Parameter	Specification
Pixel size (H × V)	14 × 200 μm
Number of total pixels	2056
Number of effective pixels	2048
Image size (H × V)	28.672 × 0.200 mm
Horizontal clock phase	2-phase
Output circuit	Two-stage MOSFET source follower
Package	24-pin ceramic DIP (refer to dimensional outline)
Window material	Quartz glass*1

\*1: Resin sealing

### Absolute maximum ratings (Ta = 25 °C, unless otherwise noted)

Parameter	Symbol	Min.	Typ.	Max.	Unit	
Operating temperature*2 *3	Topr	-50	-	+55	°C	
Storage temperature*3	Tstg	-50	-	+70	°C	
Output transistor drain voltage	VOD	-0.5	-	+25	V	
Reset drain voltage	VRD	-0.5	-	+18	V	
Test point	Vertical input source voltage	VISV	-0.5	-	+18	V
	Horizontal input source voltage	VISH	-0.5	-	+18	V
	Vertical input gate voltage	VIGV	-10	-	+15	V
	Horizontal input gate voltage	VIGH	-10	-	+15	V
Summing gate voltage	VSG	-10	-	+15	V	
Output gate voltage	VOG	-10	-	+15	V	
Reset gate voltage	VRG	-10	-	+15	V	
Transfer gate voltage	VTG	-10	-	+15	V	
Horizontal shift register clock voltage	VP1H, VP2H	-10	-	+15	V	

Note: Exceeding the absolute maximum ratings even momentarily may cause a drop in product quality. Always be sure to use the product within the absolute maximum ratings.

\*2: Package temperature

\*3: No condensation

**Operating conditions (Ta=25 °C)**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Output transistor drain voltage	VOD	12	13	14	V
Reset drain voltage	VRD	10.5	11	11.5	V
Test point	Vertical input source voltage	VISV	-	VRD	V
	Horizontal input source voltage	VISH	-	VRD	V
	Vertical input gate voltage	VIGV	-5	-4	V
	Horizontal input gate voltage	VIGH	-5	-4	V
Summing gate voltage	High	VSGH	4	5	V
	Low	VSGL	-5	-4	
Output gate voltage	VOG	2	3	4	V
Substrate voltage	VSS	-	0	-	V
Reset gate voltage	High	VRGH	4	5	V
	Low	VRGL	-5	-4	
Transfer gate voltage	High	VTGH	7	8	V
	Low	VTGL	-5	-4	
Horizontal shift register clock voltage	High	VP1HH, VP2HH	4	5	V
	Low	VP1HL, VP2HL	-5	-4	
External load resistance	RL	2.0	2.2	2.4	kΩ

**Electrical characteristics (Ta=25 °C, unless otherwise noted, operating conditions: Typ.)**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Signal output frequency*4	fc	-	1	5	MHz
Line rate	LR	-	0.48	2.37	kHz
Horizontal shift register capacitance	CP1H, CP2H	-	220	-	pF
Summing gate capacitance	CSG	-	10	-	pF
Reset gate capacitance	CRG	-	10	-	pF
Transfer gate capacitance	CTG	-	110	-	pF
Charge transfer efficiency*5	CTE	0.99995	0.99999	-	-
DC output level*4	Vout	-	8.5	-	V
Output impedance*4	Zo	-	220	-	Ω
Power consumption*4 *6	P	-	65	-	mW

\*4: The value depends on the load resistance.

\*5: Charge transfer efficiency per pixel of CCD shift register, measured at half of the full well capacity

\*6: Power consumption of the on-chip amplifier plus load resistance

**Electrical and optical characteristics (Ta=25 °C, unless otherwise noted, operating conditions: Typ.)**

Parameter	Symbol	Min.	Typ.	Max.	Unit	
Saturation output voltage	Vsat	-	Fw × Sv	-	V	
Full well capacity	Fw	150	200	-	ke <sup>-</sup>	
CCD node sensitivity	Sv	5	6	7	μV/e <sup>-</sup>	
Dark current*7	Average of all effective pixels	DSave	-	700	3500	e <sup>-</sup> /pixel/s
			-	4	20	pA/cm <sup>2</sup>
	Maximum of all effective pixels	DSmax	-	3500	17500	e <sup>-</sup> /pixel/s
			-	20	100	pA/cm <sup>2</sup>
Readout noise*8	Nr	-	25	50	e <sup>-</sup> rms	
Dynamic range*9	DR	3000	8000	-	-	
Spectral response range	λ	-	200 to 1000	-	nm	
Photoresponse nonuniformity*10 *11	PRNU	-	±3	±10	%	
Image lag*10	L	-	0.1	1	%	

\*7: Dark current is reduced to half for every 5 to 7 °C decrease in temperature.

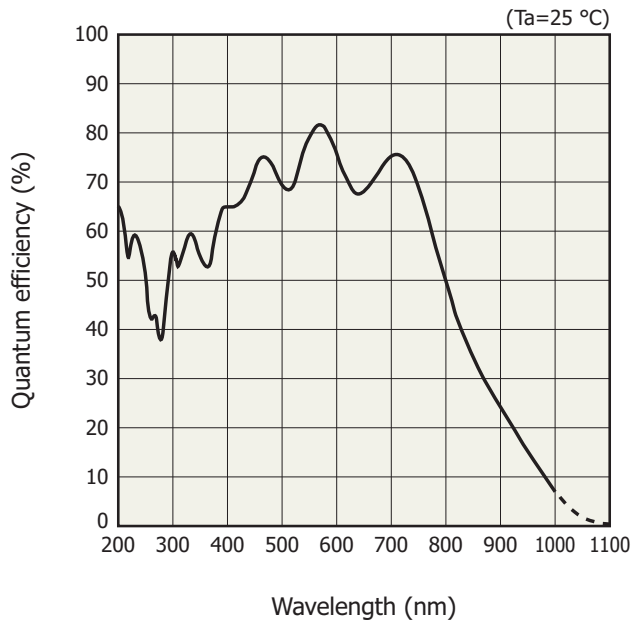
\*8: Readout frequency 1 MHz

\*9: Dynamic range = Full well capacity / Readout noise

\*10: Measured at one-half of the saturation output (full well capacity) using LED light (peak emission wavelength: 660 nm)

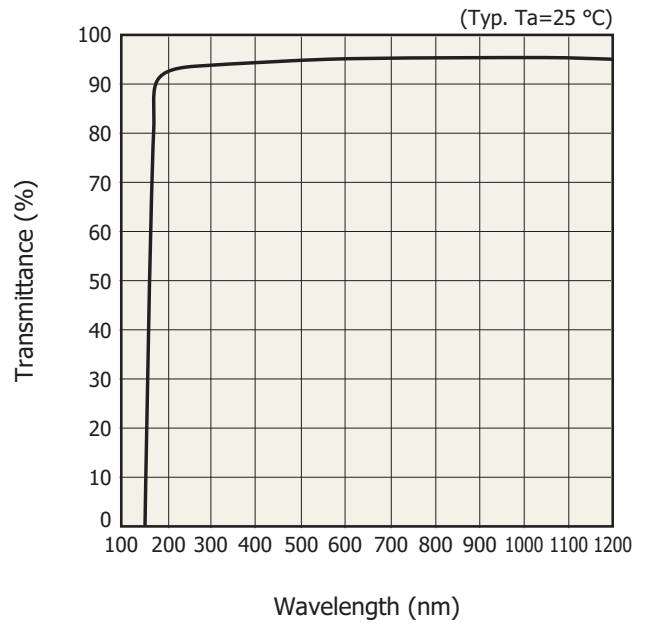
\*11: Photoresponse nonuniformity =  $\frac{\text{Fixed pattern noise (peak to peak)}}{\text{Signal}} \times 100$  [%]

▣ Spectral response (without window, typical example)\*12



KMPDB0372EA

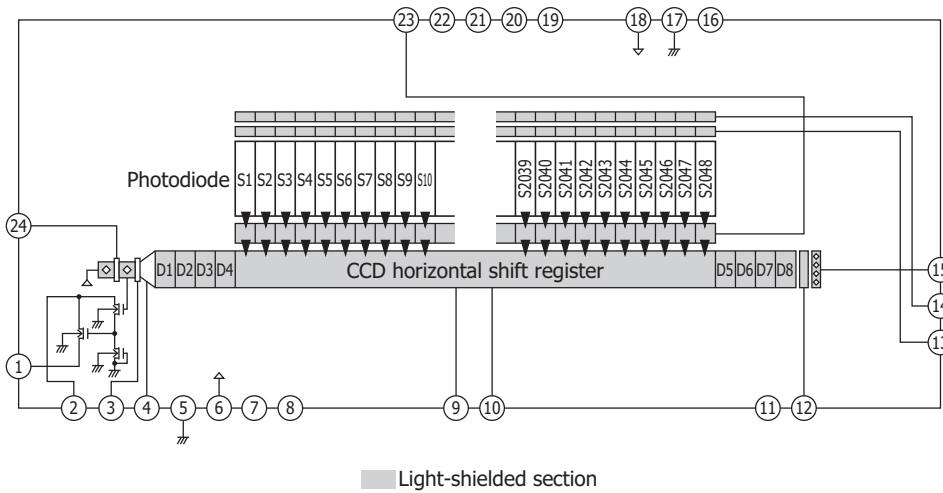
▣ Spectral transmittance characteristics of window material



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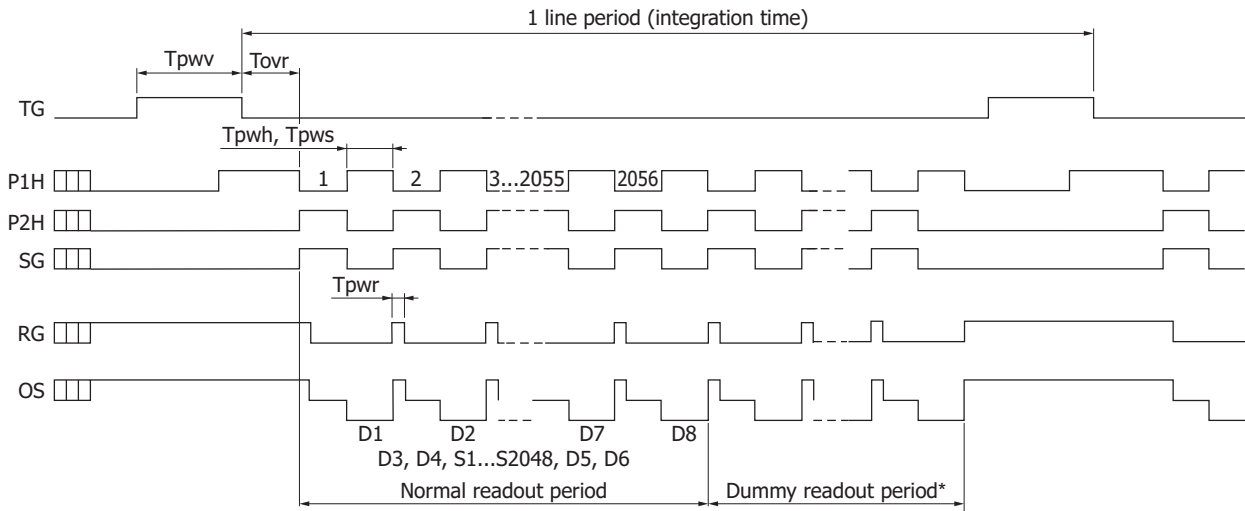
\*12: Spectral response with quartz glass is decreased according to the spectral transmittance characteristic of window material.

▣ Device structure (conceptual drawing of top view)



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**Timing chart**



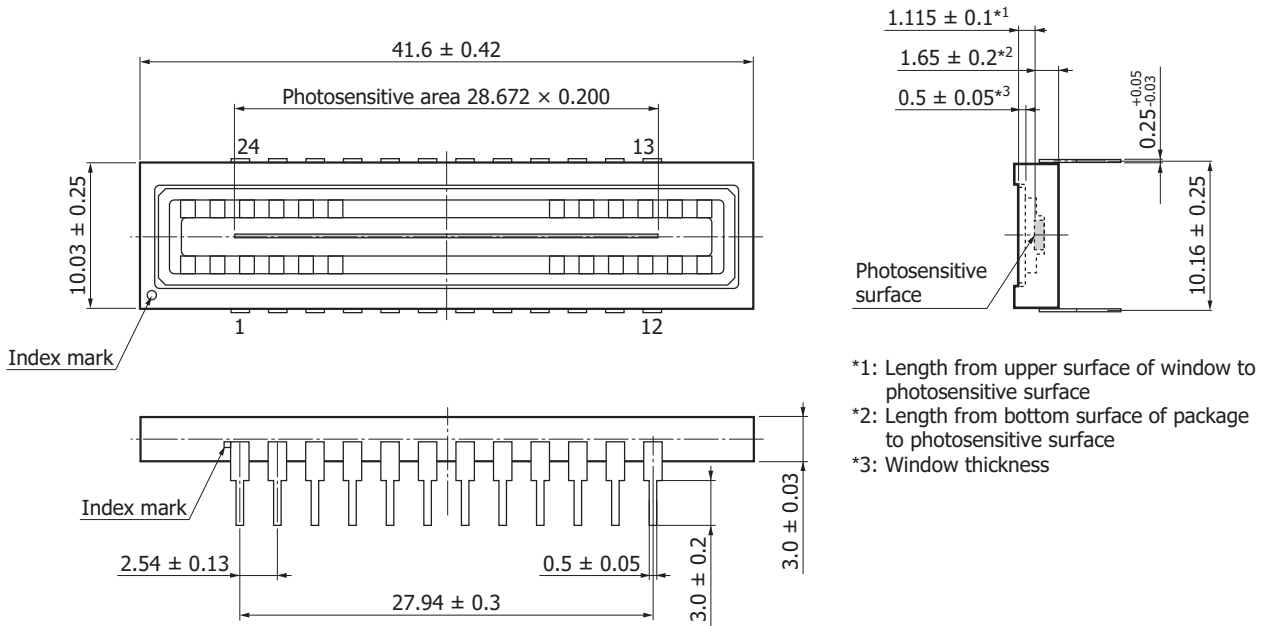
\* When making the integration time longer than the normal readout period, to carry away the dark current generated in the CCD horizontal shift register, perform dummy readout after completion of the normal readout until right before rising transfer gate pulse.

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Parameter		Symbol	Min.	Typ.	Max.	Unit
TG	Pulse width	Tpww	6	8	-	μs
	Rise and fall times	Tprv, Tpfv	20	-	-	ns
P1H, P2H*13	Pulse width	Tpwh	100	500	-	ns
	Rise and fall times	Tprh, Tpfh	10	-	-	ns
	Duty ratio	-	40	50	60	%
SG	Pulse width	Tpws	100	500	-	ns
	Rise and fall times	Tprs, Tpfs	10	-	-	ns
	Duty ratio	-	40	50	60	%
RG	Pulse width	Tpwr	10	100	-	ns
	Rise and fall times	Tprf, Tpfr	5	-	-	ns
TG-P1H	Overlap time	Tovr	1	2	-	μs

\*13: Symmetrical clock pulses should be overlapped at 50% of maximum pulse amplitude.

**Dimensional outline (unit: mm, tolerance unless otherwise noted: ±0.1)**



Note: This product is not hermetically sealed and moisture may penetrate inside the package. Avoid using or storing this product in an environment where sudden temperature and humidity changes may occur and cause condensation in the package.

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**Pin connections**

Pin no.	Symbol	Function	Remark (standard operation)
1	OS	Output transistor source	R <sub>L</sub> =2.2 kΩ
2	OD	Output transistor drain	+13 V
3	OG	Output gate	+3 V
4	SG	Summing gate	Same pulse as P2H
5	SS	Substrate	GND
6	RD	Reset drain	+11 V
7	-		
8	-		
9	P2H	CCD horizontal register clock-2	+5/-4 V
10	P1H	CCD horizontal register clock-1	+5/-4 V
11	-		
12	IGH	Test point (horizontal input gate)	-4 V
13	IGV	Test point (vertical input gate)	-4 V
14	ISV	Test point (vertical input source)	Connect it to RD.
15	ISH	Test point (horizontal input source)	Connect it to RD.
16	-		
17	SS	Substrate	GND
18	RD	Reset drain	+11 V
19	-		
20	-		
21	-		
22	-		
23	TG	Transfer gate	+8/-4 V
24	RG	Reset gate	+5/-4 V

**Related information**

■ Precautions

[http://jp.hamamatsu.com/sp/ssd/tech\\_pre\\_en.html](http://jp.hamamatsu.com/sp/ssd/tech_pre_en.html)

- Precautions for use (Image sensors)

Information described in this material is current as of November, 2012.

Product specifications are subject to change without prior notice due to improvements or other reasons. Before assembly into final products, please contact us for the delivery specification sheet to check the latest information.

Type numbers of products listed in the delivery specification sheets or supplied as samples may have a suffix "(X)" which means preliminary specifications or a suffix "(Z)" which means developmental specifications.

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